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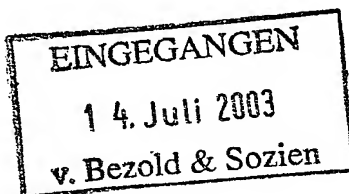
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Zeichen/Ref./Réf. 15831/EP Hz/hr	Anmeldung Nr./Application No./Demande n°/Patent Nr./Patent No./Brevet n°. 02020889.8-2208-
Anmelder/Applicant/Demandeur/Patentinhaber/Proprietor/Titulaire Staib Instrumente GmbH	

## COMMUNICATION

The European Patent Office herewith transmits as an enclosure the European search report for the above-mentioned European patent application.

If applicable, copies of the documents cited in the European search report are attached.

☒ Additional set(s) of copies of the documents cited in the European search report is (are) enclosed as well.

The following specifications given by the applicant have been approved by the Search Division:

☒ abstract

☒ title

☐ The abstract was modified by the Search Division and the definitive text is attached to this communication.

The following figure will be published together with the abstract:

1

## REFUND OF THE SEARCH FEE

If applicable under Article 10 Rules relating to fees, a separate communication from the Receiving Section on the refund of the search fee will be sent later.



**ANNEX TO THE EUROPEAN SEARCH REPORT  
ON EUROPEAN PATENT APPLICATION NO.**

EP 02 02 0889

This annex lists the patent family members relating to the patent documents cited in the above-mentioned European search report. The members are as contained in the European Patent Office EDP file on  
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07-07-2003

Patent document cited in search report		Publication date		Patent family member(s)	Publication date
US 3777211	A	04-12-1973	NL	7012671 A	29-02-1972
			CA	946985 A1	07-05-1974
			DE	2138766 A1	02-03-1972
			FR	2106022 A5	28-04-1972
			GB	1367940 A	25-09-1974
<hr/>					
EP 1113482	A	04-07-2001	JP	3057437 B2	26-06-2000
			JP	2000090867 A	31-03-2000
			JP	2000292378 A	20-10-2000
			EP	1113482 A1	04-07-2001
			WO	0016372 A1	23-03-2000
<hr/>					



DOCUMENTS CONSIDERED TO BE RELEVANT			
Category	Citation of document with indication, where appropriate, of relevant passages	Relevant to claim	CLASSIFICATION OF THE APPLICATION (Int.Cl.7)
X	US 3 777 211 A (KUIJPERS W) 4 December 1973 (1973-12-04)	14	H01J37/295
Y	* abstract; figures *	1	
Y	EP 1 113 482 A (JAPAN SCIENCE & TECH CORP) 4 July 2001 (2001-07-04)	1	
A	* paragraph '0044! - paragraph '0081!; figure 1 *	3,5,6, 11,12, 16,18	
D,A	RIJNDERS G J H ET AL: "IN SITU MONITORING DURING PULSED LASER DEPOSITION OF COMPLEX OXIDESUSING REFLECTION HIGH ENERGY ELECTRON DIFFRACTION UNDER HIGH OXYGENPRESSURE" APPLIED PHYSICS LETTERS, AMERICAN INSTITUTE OF PHYSICS. NEW YORK, US, vol. 70, no. 14, 7 April 1997 (1997-04-07), pages 1888-1890, XP000689523 ISSN: 0003-6951 * the whole document *	1,14	
			TECHNICAL FIELDS SEARCHED (Int.Cl.7)
			H01J
The present search report has been drawn up for all claims			
Place of search THE HAGUE		Date of completion of the search 7 July 2003	Examiner Schaub, G
<div>CATEGORY OF CITED DOCUMENTS</div> <div><div>X : particularly relevant if taken alone Y : particularly relevant if combined with another document of the same category A : technological background O : non-written disclosure P : intermediate document</div><div>T : theory or principle underlying the invention E : earlier patent document, but published on, or after the filing date D : document cited in the application L : document cited for other reasons &amp; : member of the same patent family, corresponding document</div></div>			